

Glass Frit을 이용한 염료감응 태양전지의 광 특성 연구

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Effect of Glass Frit in TiO₂ Electrode for DSSCs

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Dye sensitized solar cells(DSSCs) have been extensively studied due to their various advantages such as low production cost, colorful design, and eco-friendly process. Long optical path length is one of the most effective method to improve light harvest efficiency for DSSCs. Multi-layered TiO₂ nano-structured film with scattering layer has been studied to generate scattering effect by many researchers. It was expected that the difference of refractive index between TiO₂ particles and glass frit would generate the light scattering effect and provide the long optical path length. Therefore, to enhance the scattering effect, the frits of Bi₂O₃-B₂O₃-ZnO glass system that has the different refractive index were added to TiO₂ pastes in this study. First of all, the absorbance and haze factor of TiO₂ electrode with dyes and the refractive index of glass frit and TiO₂ were measured, respectively. To study the effect of frits, the efficiencies of DSSCs added glass frit and without glass frit were compared. Our results showed slightly higher efficiency with the different absorbance and haze factor of TiO₂ and glass frit. It was considered that the light scattering effect would be improved with adding frits to TiO₂ paste. Our preliminary studies will be useful for increasing efficiency of DSSCs.

Key words : Dye-sensitized solar cell, Photovoltaic, TiO₂ electrode, Glass frit, light harvest efficiency, DSSC

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다결정 실리콘 박형 태양전지를 위한 다결정 실리콘 씨앗층 제조 연구

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Study on the fabrication of a polycrystalline silicon (pc-Si) seed layer for the pc-Si lamelliform solar cell

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We studied the fabrication of polycrystalline silicon (pc-Si) films as seed layers for application of pc-Si thin film solar cells, in which amorphous silicon (a-Si) films in a structure of glass/Al/Al₂O₃/a-Si are crystallized by the aluminum-induced layer exchange (ALILE) process. The properties of pc-Si films formed by the ALILE process are strongly determined by the oxide layer as well as the various process parameters like annealing temperature, time, etc. In this study, the effects of the oxide film thickness on the crystallization of a-Si in the ALILE process, where the thickness of Al₂O₃ layer was varied from 4 to 50 nm. For preparation of the experimental film structure, aluminum (~300 nm thickness) and a-Si (~300 nm thickness) layers were deposited using DC sputtering and PECVD method, respectively, and Al₂O₃ layer with the various thicknesses by RF sputtering. The crystallization of a-Si was then carried out by the thermal annealing process using a furnace with the in-situ microscope. The characteristics of the produced pc-Si films were analyzed by optical microscope (OM), scanning electron microscope (SEM), Raman spectrometer, and X-ray diffractometer (XRD). As results, the crystallinity was exponentially decayed with the increase of Al₂O₃ thickness and the grain size showed the similar tendency. The maximum pc-Si grain size fabricated by ALILE process was about 45 μm at the Al₂O₃ layer thickness of 4 nm. The preferential crystal orientation was <111> and more dominant with the thinner Al₂O₃ layer. In summary, we obtained a pc-Si film not only with ~45 μm grain size but also with the crystallinity of about 75% at 4 nm Al₂O₃ layer thickness by ALILE process with the structure of a glass/Al/Al₂O₃/a-Si.

Key words : Polycrystalline silicon(다결정 실리콘), Polycrystalline silicon solar cell(다결정 실리콘 태양전지), Metal-induced crystallization(금속유도 결정화), Al-induced layer exchange(알루미늄유도 막교환), Seed layer(씨앗층)

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